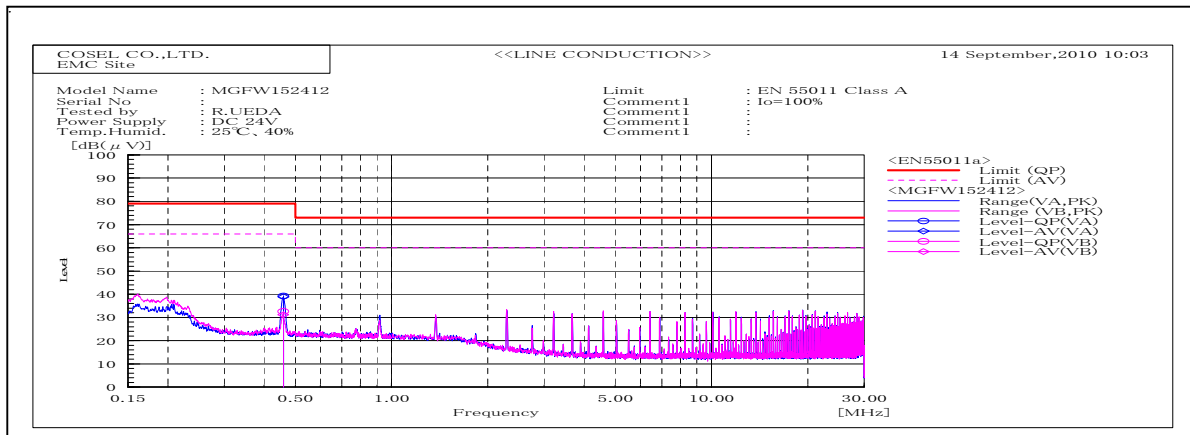
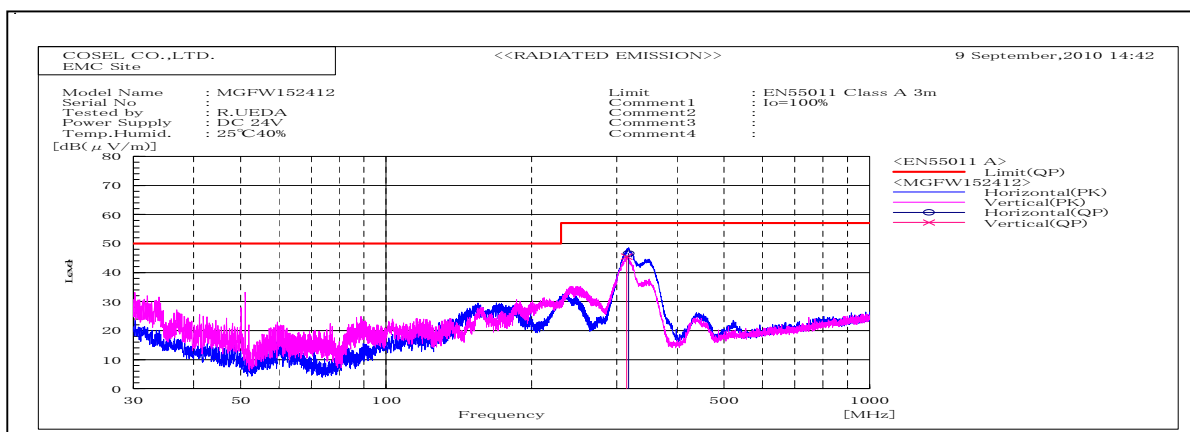


DATA SHEET		Date	21-Sep-10
Model	MGFW152412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45875		VB	22.6	21.1	10	32.6	31.1	79	66	46.4	34.9	Pass	
0.45912		VA	29.2	28.9	10.1	39.3	39	79	66	39.7	27	Pass	

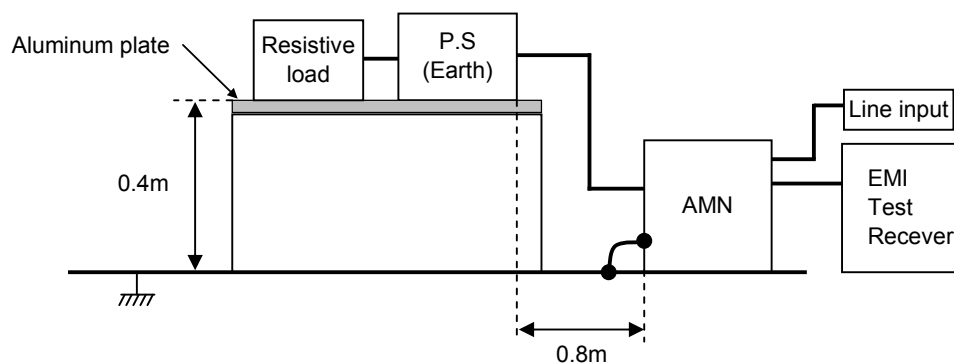


Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
314.267	V	Stable	62.8	-17.3		45.5		57	11.5	Pass	106	243	
317.336	H	Stable	63.7	-17.2		46.5		57	10.5	Pass	130	13	

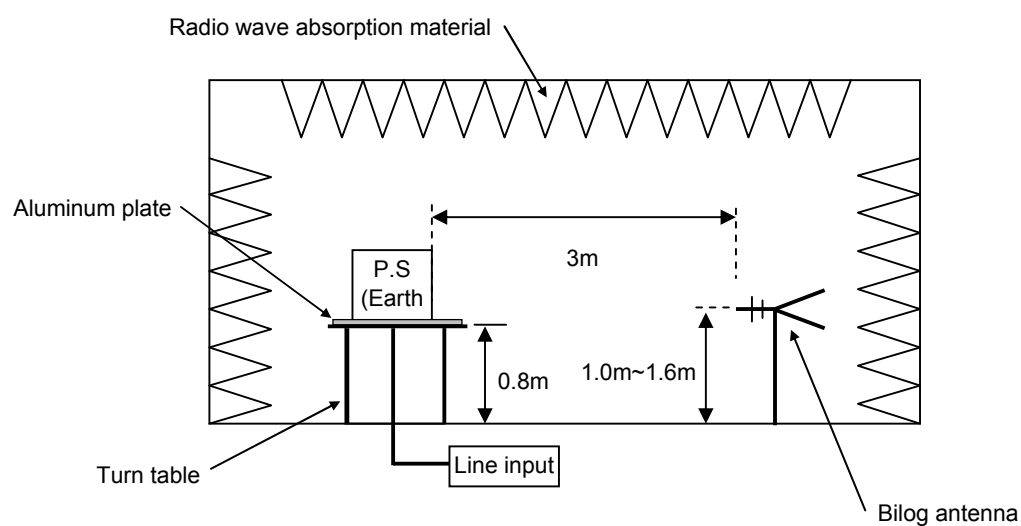
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



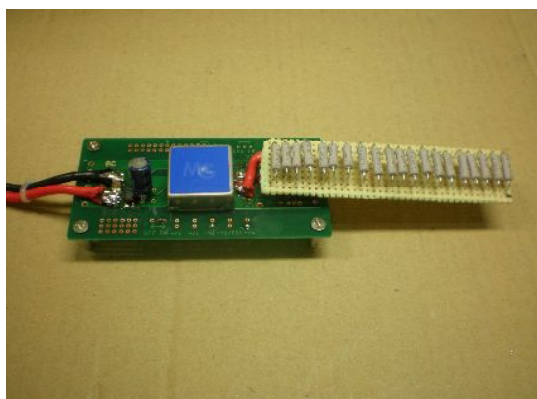


Conditions

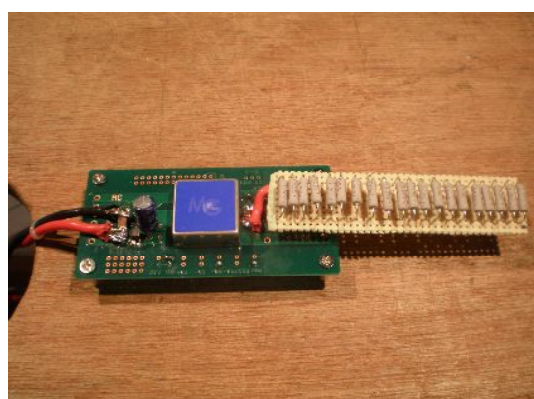
Test : EMI
Model Name : MGFS1524□□/MGFW1524□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

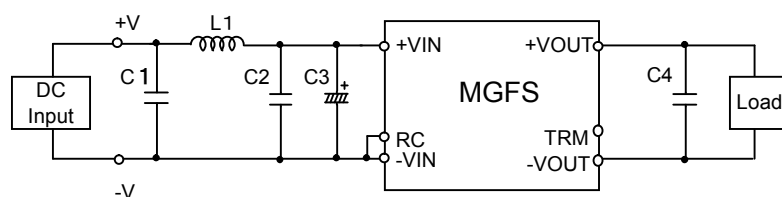


Fig.1 Testing circuitry 1

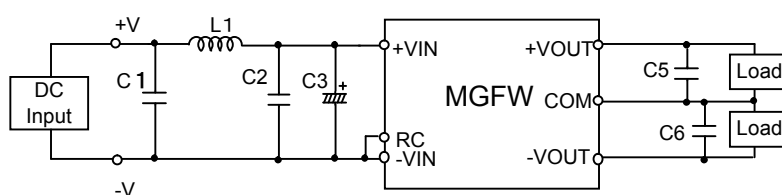


Fig.2 Testing circuitry 2

L1	:	0.5uH	CI4C-0R5	(KORIN ELECTRONICS)
C1,C2	:	50V 6.8 μ F	C4532X7R1H685MT	(TDK)
C3	:	50V 100 μ F	LXZ50VB100M	(NIPPON CHEMI-CON)
C4,C5,C6	:	25V 22 μ F	CM32X5R226K25A	(KYOCERA)